

<b>Notice of References Cited</b>	Application/Control No. 09/711,896	Applicant(s)/Patent Under Reexamination KAYANO ET AL.	
	Examiner S. Devi, Ph.D.	Art Unit 1645	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,891,663	04-1999	Tanimoto et al.	435/68.1
	B	US-			
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	D	US-			
	E	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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